

Please substitute the following abstract for the abstract presently in the application.

2 ABSTRACT

3 (Substitute) A method of diagnosing semiconductor device functional
4 testing failures by combining deterministic and functional testing to create a new test pattern
5 based on the functional failure by determining the location of and type of error in the failing
6 circuit. This is accomplished by identifying the failing vector during the functional test,
7 observing the states of the failed device by unloading the values of the latches from the
8 LSSD scan chain before the failing vector, generating a LOAD from the unloaded states of
9 the latches, applying the generated LOAD as the first event of a newly created independent
10 LSSD deterministic pattern, applying the primary inputs and Clocks that produced the
11 failure to a correctly operating device, unloading the output of the correctly operating device
12 to generate a deterministic LSSD pattern; and applying the generated deterministic LSSD
13 pattern to the failing device to diagnose the failure using existing LSSD deterministic tools

BUR120010133
SN 10/064,398